

# A New Approach to Distribution Testing

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Joint work with  
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- 1 Introduction
- 2 Uniformity Testing
- 3  $L^2$  Testers
- 4 Testing Closeness to Known Distribution
- 5 Testing Closeness to Unknown Distribution
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# Distribution Testing

**Basic statistics question:** Given a bunch of independent samples from a probability distribution (or perhaps from several), determine whether or not it has some property.

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**Basic statistics question:** Given a bunch of independent samples from a probability distribution (or perhaps from several), determine whether or not it has some property.

Example properties:

- $p$  is uniform.
- $p = q$ .
- The coordinates of  $p$  are independent.

# History

- Hypothesis testing introduced by Pearson in 1899.
- Classical problem in statistics  
[Neyman-Pearson33, Lehman-Romano05]
- Recently taken up by the TCS community  
[Goldreich-Ron00, BFFKRW FOCS00/JACM13]

# Closeness

## Problem

Cannot distinguish between  $p$  with property and arbitrarily close  $p'$  without.

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## Solution

Distinguish between

- $p$  has property.
- $p$  is far (usually in  $L^1$ ) from any distribution with property.

# Continuous

## Problem

Cannot distinguish between continuous distribution and discrete distribution with large random support.



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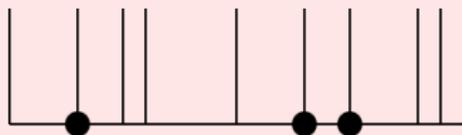
## Solutions

- Consider only *structured*, low-complexity distributions.
- Consider only discrete distributions on finite domain.

# Continuous

## Problem

Cannot distinguish between continuous distribution and discrete distribution with large random support.



## Solutions

- Consider only *structured*, low-complexity distributions.
- Consider only discrete distributions on finite domain.

We will focus on the latter.

# Notation

- Distributions  $p, q$  on  $[n] := \{1, 2, \dots, n\}$ .
- $p_i := \Pr(p = i), q_i := \Pr(q = i)$ .
- Question like: distinguish between
  - ▶  $p = q$
  - ▶  $\|p - q\|_1 \geq \epsilon$

with at least  $2/3$  probability of success.

# Goal

Want:

- Number of samples information-theoretically optimal.
- Runtime polynomial (or even linear) in number of samples.

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# Simple Question

Distinguish between:

- $p$  is the uniform distribution.
- $\|p - U_n\|_1 = \Omega(1)$ .

# Stats 101 Answer

- Take  $m$  samples from  $p$ .
- Let  $X_i$  be from bin  $i$ .
- Note  $X_i \approx \text{Gaussian}$ .
- Compute

$$Z := \sum_{i=1}^n (X_i - m/n)^2$$

and compare to appropriate  $\chi^2$  distribution.

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Problem: Need  $\Omega(n)$  samples for Gaussian approximation.

# Improvement

## Observation [Goldreich-Ron]

Taking samples from the uniform distribution gives fewer expected collisions than from any other distribution.

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- Take  $m$  samples.
- Count collisions.
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# Improvement

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Taking samples from the uniform distribution gives fewer expected collisions than from any other distribution.

## Algorithm

- Take  $m$  samples.
- Count collisions.
- Compare to number expected under uniform distribution.

Takes about  $\sqrt{n}$  samples to get collision. Sample complexity  $O(\sqrt{n})$ .

# Quadratic Testers

- Both testers use quadratic test statistics.
- Very natural thing to do.
- As we will see quite powerful.

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# Problem

- Distributions  $p, q$  on  $[n]$ .
- Take  $m$  samples from each.
- Distinguish between
  - ▶  $p = q$
  - ▶  $p$  far from  $q$

# Simple Tester

- $X_i$  number of samples from  $p$  in  $i^{\text{th}}$  bin.
- $Y_i$  number of samples from  $q$  in  $i^{\text{th}}$  bin.
- Test statistic

$$Z = \sum_{i=1}^n (X_i - Y_i)^2.$$

# Poissonization

## Trick

Take  $\text{Poi}(m)$  samples from  $p$  and  $\text{Poi}(m)$  samples from  $q$ .

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## Trick

Take  $\text{Poi}(m)$  samples from  $p$  and  $\text{Poi}(m)$  samples from  $q$ .

- Makes  $X_i, Y_i$  independent.
- $X_i \sim \text{Poi}(mp_i), Y_i \sim \text{Poi}(mq_i)$
- Likely doesn't change total number of samples by much.

# Expectation

Have

$$\mathbb{E}[(X_i - Y_i)^2] = m^2(p_i - q_i)^2 + m(p_i + q_i).$$

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Fix:

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Then

$$\begin{aligned}\mathbb{E}[Z] &= m^2 \|p - q\|_2^2 \\ \text{Var}(Z) &= O(m^3 \|p - q\|_2^2 \|p + q\|_2 + m^2 \|p + q\|_2^2)\end{aligned}$$

# $L^2$ Tester

## $L^2$ Tester [Chan-Diakonikolas-Valiant-Valiant]

There is a tester that distinguishes between  $p = q$  and  $\|p - q\|_2^2 \geq \epsilon^2$  in expected  $O(\|p + q\|_2 / \epsilon^2)$  samples.

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### Note

By first testing if  $\|p\|_2 \approx \|q\|_2$ , can reduce to  $O(\min(\|p\|_2, \|q\|_2) / \epsilon^2 + \min(1/\|p\|_2, 1/\|q\|_2))$  samples.

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### Note

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### Note II

In fact, this tester is *tolerant*. It can distinguish between  $\|p - q\|_2^2 \leq \epsilon^2/2$  and  $\|p - q\|_2^2 \geq \epsilon^2$ .

# Main New Idea

Solve *all* problems by reducing to this as a black box.

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# Problem

Compare  $p$  to explicitly known distribution.

- Given explicit distribution  $q$  on  $[n]$ .
- Given  $m$  samples from  $p$  on  $[n]$ .
- Distinguish between
  - ▶  $p = q$
  - ▶  $\|p - q\|_1 \geq \epsilon$ .

# Using $L^2$ Tester

Need to distinguish between  $p = q$  and  $\|p - q\|_2^2 \geq \epsilon^2/n$ .

- Simulate samples from  $q$ .
- Takes  $O(n\|q\|_2/\epsilon^2)$  samples.

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- If  $q$  near uniform, this is  $O(\sqrt{n}/\epsilon^2)$ , which is optimal.
- If  $\|q\|_2$  is large, test statistic has too much variance.

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## Question

How do we deal with this?

# Previous Work

- **[Batu-Fortnow-Kumar-Rubinfeld-Smith-White '00]**: Split bins into buckets in which  $q$  is near-uniform.
- **[Valiant-Valiant '14]**: Modify the test statistic to give less weight to heavy bins.

# Our Technique

Divide  $i^{\text{th}}$  bin into  $\lceil nq_i \rceil$  equally sized bins. Have new distributions  $p', q'$ .

## Facts

- $\|p' - q'\|_1 = \|p - q\|_1$ .
- Can sample from  $p'$ .
- New domain size  $O(n)$ .
- $q'$  approximately uniform.

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- $\|p' - q'\|_1 = \|p - q\|_1$ .
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Requires  $O(\sqrt{n}/\epsilon^2)$  samples.

# Reduction

Essentially, we reduced to the case where  $q_i = O(1/n)$  for all  $i$ .

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Recent improvement by Goldreich shows how to reduce to  $q = \text{Uniform}$ .

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- What happens if instead  $q$  is *unknown* and we are only given sample access?
- We no longer know how to break bins up or reweight  $Z$ .
- Testing is actually *harder*. There is a lower bound of

$$\Omega(\max(\sqrt{n}/\epsilon^2, n^{2/3}/\epsilon^{4/3}))$$

samples by Chan-Diakonikolas-Valiant-Valiant.

# Previous Work

- **[Batu-Fisher-Fortnow-Kumar-Rubinfeld-White '00]**: Learn the heavy bins of  $q$ , and run  $L^2$  tester on light bins. (Gives  $O(n^{2/3} \log(n)/\epsilon^{8/3})$  samples)
- **[Valiant '08]**: Learn heavy bins of  $q$  and see if higher moments of  $p$  and  $q$  on low bins match. (Gives  $O(n^{2/3})$  samples for constant  $\epsilon$ )
- **[Chan-Diakonikolas-Valiant-Valiant '14]**: Uses different test statistic

$$\sum_i \frac{(X_i - Y_i)^2 - X_i - Y_i}{X_i + Y_i}.$$

Sample optimal.

# Idea

- Need to divide heavier bins into more pieces.
- How to detect heavy bins?

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- How to detect heavy bins?
- Use samples.

# Our Technique

Take  $\text{Poi}(k)$  samples from  $q$ . If  $a_i$  samples from bin  $i$ , divide into  $a_i + 1$  pieces.

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$$\|q'\|_2^2 = \sum_i (a_i + 1) \left( \frac{q_i}{a_i + 1} \right)^2 = \sum_i \frac{q_i^2}{a_i + 1}.$$

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$$\mathbb{E}[\|q'\|_2^2] = \sum_i q_i^2 \mathbb{E}[1/(a_i + 1)] = \sum_i O(q_i^2 / (kq_i)) = O(1/k).$$

# Algorithm

## Algorithm

- Let  $k = \min(n, n^{2/3}/\epsilon^{4/3})$ .
- Take  $\text{Poi}(k)$  samples from  $q$ , and divide bins based on samples.
- Run  $L^2$  tester to see if  $p' = q'$  or  $\|p' - q'\|_1 \geq \epsilon$ .

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Likely have

- $O(n)$  bins.
- $\|q'\|_2 = O(1/\sqrt{k})$ .

# Samples Needed

$$O(k + nk^{-1/2}\epsilon^{-2}) = O(\max(\sqrt{n}/\epsilon^2, n^{2/3}/\epsilon^{4/3})).$$

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$$O(k + nk^{-1/2}\epsilon^{-2}) = O(\max(\sqrt{n}/\epsilon^2, n^{2/3}/\epsilon^{4/3})).$$

This also works if you can take *unequal* numbers of samples from the two distributions.

- $O(m)$  samples from  $p$
- $O(k + m)$  samples from  $q$
- Where  $m = O(\sqrt{n}/\epsilon^2 + nk^{-1/2}/\epsilon^2)$ .

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# Problem

$p$  a distribution on  $[n] \times [m]$  for  $n \geq m$ . Given samples from  $p$  distinguish between cases:

- The coordinates of  $p$  are independent.
- $p$  is at least  $\epsilon$ -far from any distribution with independent coordinates.

# Previous Work

## Upper bounds

- **[Batu-Fisher-Fortnow-Kumar-Rubinfeld-White '01]:**  $\tilde{O}(n^{2/3}m^{1/3}\text{poly}(1/\epsilon))$ .
- **[Acharya-Daskalakis-Kamath '15]:**  $O(n/\epsilon^2)$  for  $n = m$ .

# Previous Work

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- **[Acharya-Daskalakis-Kamath '15]:**  $O(n/\epsilon^2)$  for  $n = m$ .

## Lower bounds

- **[Levi-Ron-Rubinfeld '11]:**  $\tilde{\Omega}(n^{2/3}m^{1/3})$  for constant error.
- **[Diakonikolas-K '16]:**  
 $\Omega(\max(n^{2/3}m^{1/3}/\epsilon^{4/3}, \sqrt{nm}/\epsilon^2))$

# Our Technique

- Compare  $p$  to  $q = p_1 \times p_2$ .
- Need to flatten  $q$ . Do by flattening  $p_1, p_2$ .

# Algorithm

## Algorithm

- Take  $\text{Poi}(m)$  samples from  $p_2$ , use to subdivide bins of  $[m]$ .
- Let  $k = \min(n, n^{2/3}m^{1/3}/\epsilon^{4/3})$ .
- Take  $\text{Poi}(k)$  samples from  $p_1$ , use to subdivide bins of  $[n]$ .
- Use  $L^2$  tester to distinguish  $p' = q'$  or  $\|p' - q'\|_1 \geq \epsilon$ .

# Analysis

Probably have:

- New array  $O(n) \times O(m)$ .
- $\|p'_1\|_2 = O(1/\sqrt{k})$ ,  $\|p'_2\|_2 = O(1/\sqrt{m})$ .

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Samples needed:

$$\begin{aligned} & O(k + m + nmk^{-1/2}m^{-1/2}/\epsilon^2) \\ & = O(\max(n^{2/3}m^{1/3}/\epsilon^{4/3}, \sqrt{nm}/\epsilon^2)). \end{aligned}$$

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Optimal!

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# Worst Case

Testing identity to a known distribution requires  $O(\sqrt{n}/\epsilon^2)$  samples, but only for worst-case  $q$ . This lower bound is not hard to prove for  $q$  uniform or nearly uniform, but for other  $q$  you can often do better.

# Instance Optimality

[Valiant-Valiant '14] provide an *instance optimal* tester. That is a tester that for each  $q$  gives a tester with the fewest number of samples *for that*  $q$ . The complexity is (usually)  $\Theta(\|q\|_{2/3}/\epsilon^2)$ .

# Instance Optimality

[Valiant-Valiant '14] provide an *instance optimal* tester. That is a tester that for each  $q$  gives a tester with the fewest number of samples *for that*  $q$ . The complexity is (usually)  $\Theta(\|q\|_{2/3}/\epsilon^2)$ .

The basic technique involves a careful reweighting of the  $L^2$  tester.

# Our Results

Using the  $L^2$  tester as a black box, we can get within polylogarithmic factors.

## Algorithm

- Divide bins into (logarithmically many) categories based on  $\lfloor \log(q_i) \rfloor$ .
- Test that  $p$  assigns approximately the right mass to each category.
- For each category,  $C$ , test whether  $(p|C) = (q|C)$  or  $\|(p|C) - (q|C)\|_1 \geq \epsilon / \Pr(C) \text{polylog}(n/\epsilon)$ .

# Analysis

Testing over categories is easy. Consider a single category  $C$ .

- All bins mass  $\Theta(x)$ .
- $m$  total bins.
- $\Pr(C) = \Theta(mx)$ .

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- All bins mass  $\Theta(x)$ .
- $m$  total bins.
- $\Pr(C) = \Theta(mx)$ .
- Need  $\text{polylog}(n/\epsilon)\sqrt{m}/(\epsilon/(mx))^2 = \text{polylog}(n/\epsilon)m^{5/2}x^2/\epsilon^2$  samples from  $p|C$ .
- Need  $\text{polylog}(n/\epsilon)m^{3/2}x/\epsilon^2$  samples from  $p$ .

# Analysis

$$\|q\|_{2/3} \approx \left( \max_C (m x^{2/3}) \right)^{3/2} = \max_C (m^{3/2} x).$$

Sample complexity  $\text{polylog}(n/\epsilon) \|q\|_{2/3} / \epsilon^2$ .

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Sample complexity  $\text{polylog}(n/\epsilon) \|q\|_{2/3} / \epsilon^2$ .

Correct up to polylogarithmic factors.

# Unknown $q$

Perhaps more surprisingly, we can do almost as well without knowing  $q$  ahead of time.

## Idea

- Take  $m$  samples from  $q$ .
- Divide bins into categories based of  $\lfloor \log(\text{samples}) \rfloor$ .
- Check that  $p$  assigns roughly same mass to categories.
- Test whether restriction of  $p$  to categories approximates  $q$ .

# Analysis

- Bins with more than  $1/m$  mass sorted into category with other bins of approximately the same size.
- On these categories looks like instance optimal tester.
- Remaining bin uses  $L^2$  tester.

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- On these categories looks like instance optimal tester.
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## Complexity

$$\text{polylog}(n/\epsilon) \min_m \left( m + \|q\|_{2/3}/\epsilon^2 + \|q^{<1/m}\|_2 \|q^{<1/m}\|_0/\epsilon^2 \right).$$

# Discussion

- When  $\epsilon$  small  $\tilde{O}(\|q\|_{2/3}/\epsilon^2)$ .

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- When  $\epsilon$  small  $\tilde{O}(\|q\|_{2/3}/\epsilon^2)$ .
- Taking  $m = \min(n, n^{2/3}/\epsilon^{4/3})$  get

$$\tilde{O}(\max(\sqrt{n}/\epsilon^2, n^{2/3}/\epsilon^{4/3})).$$

- Only this bad when  $\approx m$  bins with mass  $\approx 1/m$  and  $\approx n$  bins of mass  $\approx 1/n$ .

# Instance Optimal for Unknown $q$

Unfortunately, there is no way to have instance optimal when  $q$  is unknown since different  $q$  do not give rise to different problems.

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Unfortunately, there is no way to have instance optimal when  $q$  is unknown since different  $q$  do not give rise to different problems.

Can find algorithms that work better with certain  $q$  or better with  $q$  with certain structure, but you need to choose which structure to take advantage of. What the “right” notion is here is still an open problem.

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# Other Applications

We also get (nearly) optimal results for:

- Independence testing in higher dimensions.
- Properties of collections of distributions.
- Testing histograms.
- Testing with Hellinger metric.

# Future Directions

- Structured distributions.  
Active area (especially for high-dimensional distributions).
- Correct probability of error.  
[Diakonikolas-Gouleakis-Peebles-Price '16] give correct result for identity testing.
- Optimal constants.  
Some work by [Huang-Meyn '14]
- Beyond worst case analysis.